

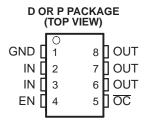
POWER-DISTRIBUTION SWITCHES

FEATURES

- 33-mΩ (5-V Input) High-Side MOSFET Switch
- Short-Circuit and Thermal Protection
- Overcurrent Logic Output
- Operating Range: 2.7 V to 5.5 V
- Logic-Level Enable InputTypical Rise Time: 6.1 ms
- Undervoltage Lockout
- Maximum Standby Supply Current: 10 μA
- No Drain-Source Back-Gate Diode
- Available in 8-pin SOIC and PDIP Packages

- Ambient Temperature Range, –40°C to 85°C
- 2-kV Human-Body-Model, 200-V Machine-Model ESD Protection
- UL Listed

 File No. E169910

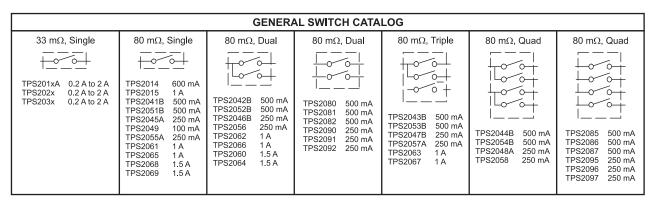


DESCRIPTION

The TPS203x family of power distribution switches is intended for applications where heavy capacitive loads and short circuits are likely to be encountered. These devices are $50\text{-m}\Omega$ N-channel MOSFET high-side power switches. The switch is controlled by a logic enable compatible with 5-V logic and 3-V logic. Gate drive is provided by an internal charge pump designed to control the power-switch rise times and fall times to minimize current surges during switching. The charge pump requires no external components and allows operation from supplies as low as 2.7 V.

When the output load exceeds the current-limit threshold or a short is present, the TPS203x limits the output current to a safe level by switching into a constant-current mode, pulling the overcurrent (\overline{OC}) logic output low. When continuous heavy overloads and short circuits increase the power dissipation in the switch, causing the junction temperature to rise, a thermal protection circuit shuts off the switch to prevent damage. Recovery from a thermal shutdown is automatic once the device has cooled sufficiently. Internal circuitry ensures the switch remains off until valid input voltage is present.

The TPS203x devices differ only in short-circuit current threshold. The TPS2030 limits at 0.3-A load, the TPS2031 at 0.9-A load, the TPS2032 at 1.5-A load, the TPS2033 at 2.2-A load, and the TPS2034 at 3-A load (see Available Options). The TPS203x is available in an 8-pin small-outline integrated-circuit (SOIC) package and in an 8-pin dual-in-line (DIP) package and operates over a junction temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





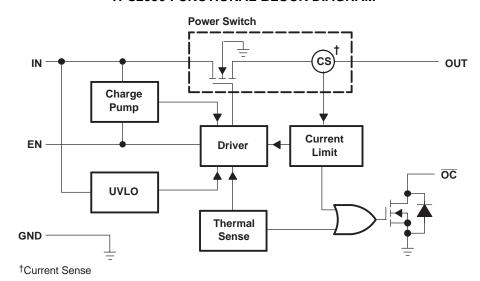
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

AVAILABLE OPTIONS

		RECOMMENDED MAXIMUM	TYPICAL SHORT-CIRCUIT	PACKAGED DEVICES ⁽¹⁾		
T _A	ENABLE	CONTINUOUS LOAD CURRENT (A)	CURRENT LIMIT AT 25°C (A)	SMALL OUTLINE (D) ⁽²⁾	PLASTIC DIP (P)	
	Active high		0.2	0.3	TPS2030D	TPS2030P
			0.6	0.9	TPS2031D	TPS2031P
–40°C to 85°C		1	1.5	TPS2032D	TPS2032P	
		1.5	2.2	TPS2033D	TPS2033P	
		2	3	TPS2034D	TPS2034P	

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
- (2) The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS2030DR)

TPS2030 FUNCTIONAL BLOCK DIAGRAM



TERMINAL FUNCTIONS

TERI	MINAL			
NAME	NO. D OR P	I/O	DESCRIPTION	
EN	4	I	Enable input. Logic high turns on power switch.	
GND	1	I	Ground	
IN	2, 3	I	Input voltage	
OC	5	0	Overcurrent. Logic output active low	
OUT	6, 7, 8	0	Power-switch output	



DETAILED DESCRIPTION

POWER SWITCH

The power switch is an N-channel MOSFET with a maximum on-state resistance of 50 m Ω (V_{I(IN)} = 5 V). Configured as a high-side switch, the power switch prevents current flow from OUT to IN and IN to OUT when disabled.

CHARGE PUMP

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires very little supply current.

DRIVER

The driver controls the gate voltage of the power switch. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the driver incorporates circuitry that controls the rise times and fall times of the output voltage. The rise and fall times are typically in the 2-ms to 9-ms range.

ENABLE (EN)

The logic enable disables the power switch, the bias for the charge pump, driver, and other circuitry to reduce the supply current to less than 10 μ A when a logic low is present on EN . A logic high input on EN restores bias to the drive and control circuits and turns the power on. The enable input is compatible with both TTL and CMOS logic levels.

OVERCURRENT (OC)

The \overline{OC} open drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output will remain asserted until the overcurrent or overtemperature condition is removed.

CURRENT SENSE

A sense FET monitors the current supplied to the load. The sense FET measures current more efficiently than conventional resistance methods. When an overload or short circuit is encountered, the current-sense circuitry sends a control signal to the driver. The driver, in turn, reduces the gate voltage and drives the power FET into its saturation region, which switches the output into a constant current mode and holds the current constant while varying the voltage on the load.

THERMAL SENSE

An internal thermal-sense circuit shuts off the power switch when the junction temperature rises to approximately 140°C. Hysteresis is built into the thermal sense circuit. After the device has cooled approximately 20°C, the switch turns back on. The switch continues to cycle off and on until the fault is removed.

UNDERVOLTAGE LOCKOUT

A voltage sense circuit monitors the input voltage. When the input voltage is below approximately 2 V, a control signal turns off the power switch.



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

			VALUE	UNIT
V _{I(IN)} (2)	Input voltage range		-0.3 to 6	V
V _{O(OUT)} ⁽²⁾	Output voltage range		-0.3 to V _{I(IN)} + 0.3	V
V _{I(EN)}	Input voltage range		-0.3 to 6	V
I _{O(OUT)}	Continuous output current		Internally limited	
	Continuous total power dissipation		See Dissipation Rating Table	
T _J	Operating virtual junction temperature	range	-40 to 125	°C
T _{stg}	Storage temperature range		-65 to 150	°C
		Human body model	2	kV
ESD	Electrostatic discharge protection:	Machine model	200	V
		Charged device model (CDM)	750	V

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
D	725 mW	5.8 mW°C	464 mW	377 mW
Р	1175 mW	9.4 mW°C	752 mW	611 mW

RECOMMENDED OPERATING CONDITIONS

			MIN	MAX	UNIT
	Input voltage	V _{I(IN)}	2.7	5.5	٧
	Input voltage	V _{I(EN)}	0	5.5	٧
		TPS2030	0	0.2	
		TPS2031	0	0.6	
Io	Continuous output current	TPS2032	0	1	Α
		TPS2033	0	1.5	
		TPS2034	0	2	
T_{J}	Operating virtual junction ter	mperature	-40	125	°C

⁽²⁾ All voltages are with respect to GND.



ELECTRICAL CHARACTERISTICS

over recommended operating junction temperature range, $V_{I(IN)} = 5.5 \text{ V}$, $I_O = \text{rated current}$, EN = 5 V (unless otherwise noted)

POWER	SWITCH							
	PARAMETER	1	TEST CONDITIO	NS ⁽¹⁾	MIN	TYP	MAX	UNIT
		$V_{I(IN)} = 5 V$,	T _J = 25°C,	I _O = 1.8 A		33	36	
		$V_{I(IN)} = 5 V$,	$T_J = 85^{\circ}C$,	$I_{O} = 1.8 \text{ A}$		38	46	
		$V_{I(IN)} = 5 V$,	$T_J = 125^{\circ}C$,	$I_{O} = 1.8 \text{ A}$		44	50	
		$V_{I(IN)} = 3.3 V,$	$T_J = 25^{\circ}C$,	$I_{O} = 1.8 \text{ A}$		37	41	
		$V_{I(IN)} = 3.3 V,$	$T_J = 85^{\circ}C$,	$I_{O} = 1.8 \text{ A}$		43	52	
-	Static drain-source on-state resistance	$V_{I(IN)} = 3.3 V,$	$T_J = 125^{\circ}C$,	$I_{O} = 1.8 \text{ A}$		51	61	mΩ
r _{DS(on)}	Static drain-source on-state resistance	$V_{I(IN)} = 5 V$,	$T_J = 25^{\circ}C$,	$I_{O} = 0.18 A$		30	34	mΩ
		$V_{I(IN)} = 5 V$,	$T_J = 85^{\circ}C$,	$I_{O} = 0.18 A$		35	41	
		$V_{I(IN)} = 5 V$,	$T_J = 125^{\circ}C$,	$I_{O} = 0.18 A$		39	47	
		$V_{I(IN)} = 3.3 V,$	$T_J = 25^{\circ}C$,	$I_{O} = 0.18 A$		33	37	
		$V_{I(IN)} = 3.3 V,$	$T_J = 85^{\circ}C$,	$I_{O} = 0.18 A$		39	46	
		$V_{I(IN)} = 3.3 V,$	$T_J = 125^{\circ}C$,	$I_{O} = 0.18 A$		44	56	
	Rise time, output	$\begin{aligned} &V_{I(IN)} = 5.5 \text{ V}, \\ &C_L = 1 \mu\text{F}, \end{aligned}$	$T_J = 25^{\circ}C$, $R_L = 10 \Omega$			6.1		
t _r Rise time, output	Kise time, output	$\label{eq:VI(IN)} \begin{array}{l} V_{I(IN)} = 2.7 \ V, \\ C_L = 1 \ \mu F, \end{array}$	$T_J = 25^{\circ}C$, $R_L = 10 \Omega$			8.6		ms
	Fall time output	$V_{I(IN)} = 5.5 \text{ V},$ $C_L = 1 \mu\text{F},$	$T_J = 25^{\circ}C$, $R_L = 10 \Omega$			3.4		ma
t _f	Fall time, output	$V_{I(IN)} = 2.7 \text{ V},$ $C_L = 1 \mu\text{F},$				3		ms

⁽¹⁾ Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

ENABLE INPUT (EN)							
	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT		
V_{IH}	high-level input voltage	$2.7 \text{ V} \le \text{V}_{\text{I(IN)}} \le 5.5 \text{ V}$	2		V		
V _{IL}	Low level input valtage	$4.5 \text{ V} \le \text{V}_{\text{I(IN)}} \le 5.5 \text{ V}$		0.8	W		
	Low-level input voltage	$2.7 \text{ V} \le \text{V}_{\text{I(IN)}} \le 4.5 \text{ V}$		0.5	V		
I _I	Input current	$EN = 0 V or EN = V_{I(IN)}$	-0.5	0.5	μΑ		
t _{on}	Turnon time	$C_L = 100 \ \mu F, \ R_L = 10 \ \Omega$		20			
t _{off}	Turnoff time	$C_L = 100 \ \mu F, \ R_L = 10 \ \Omega$		40	ms		

CUR	CURRENT LIMIT							
	PARAMETER	TEST CONDITIONS ⁽¹⁾		MIN	TYP	MAX	UNIT	
		TPS2030	0.22	0.3	0.4			
		T _J = 25°C, V _I = 5.5 V, OUT connected to GND, Device enable into short circuit	TPS2031	0.66	0.9	1.1		
Ios	Short-circuit output current		TPS2032	1.1	1.5	1.8	Α	
		Devide driable line drient driedit	TPS2033	1.65	2.2	2.7		
			TPS2034	2.2	3	3.8		

⁽¹⁾ Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.



ELECTRICAL CHARACTERISTICS (Continued)

over recommended operating junction temperature range, $V_{I(IN)} = 5.5 \text{ V}$, $I_O = \text{rated current}$, EN = 5 V (unless otherwise noted)

SUPPLY CURRENT							
PARAMETER TEST CONDITIONS		MIN	TYP	MAX	UNIT		
Cupply current low lovel cutput	No Lood on OUT	EN O	T _J = 25°C		0.3	1	
Supply current, low-level output	No Load on OUT	EN = 0	40°C ≤ T _J ≤ 125°C			10	μA
Oursels suggest high level sets of the New York COUT.		T _J = 25°C		58	75		
Supply current, high-level output	No Load on OUT	$EN = V_{I(IN)}$	40°C ≤ T _J ≤ 125°C		75	100	μA
Leakage current	OUT connected to ground	EN = 0	40°C ≤ T _J ≤ 125°C		10		μΑ

UNDERVOLTAGE LOCKOUT					
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Low-level input voltage		2		2.5	V
Hysteresis	T _J = 25°C		100		mV
OVERCURRENT (OC)					
Output low voltage	$I_O = 10 \text{ mA}, V_{OL(\overline{OC})}$			0.4	V
Off-state current ⁽¹⁾	$V_{O} = 5 \text{ V}, V_{O} = 3.3 \text{ V}$			1	μΑ

⁽¹⁾ Specified by design, not production tested.



PARAMETER MEASUREMENT INFORMATION

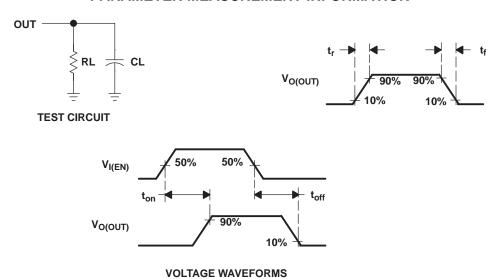


Figure 1. Test Circuit and Voltage Waveforms

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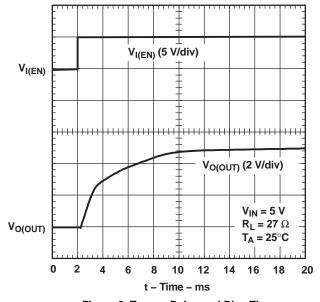


Figure 2. Turnon Delay and Rise Time

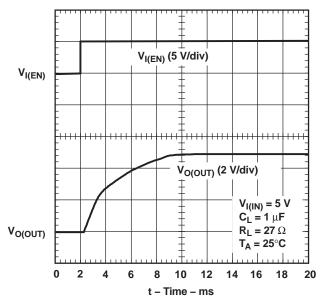


Figure 4. Turnon Delay and Rise Time With 1-µF Load

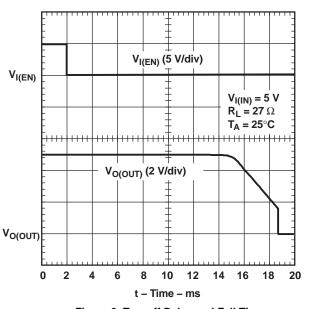


Figure 3. Turnoff Delay and Fall Time

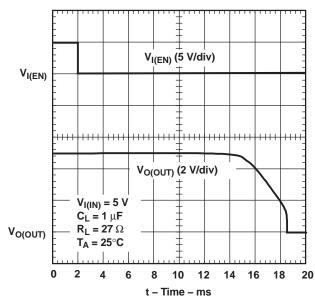


Figure 5. Turnoff Delay and Fall Time With 1-µF Load



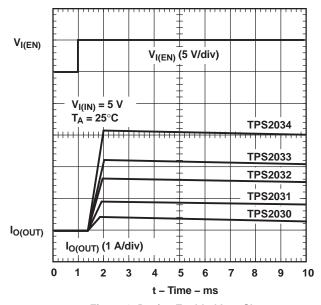


Figure 6. Device Enabled Into Short

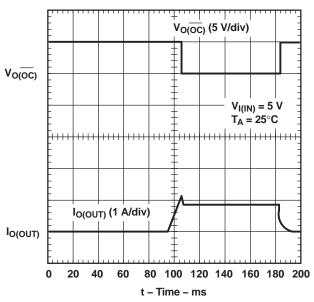


Figure 8. TPS2031, Ramped Load on Enabled Device

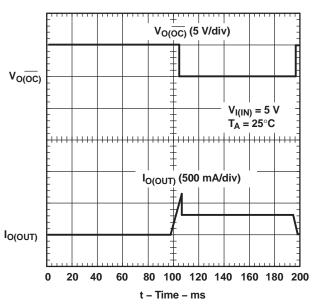


Figure 7. TPS2030, Ramped Load on Enabled Device

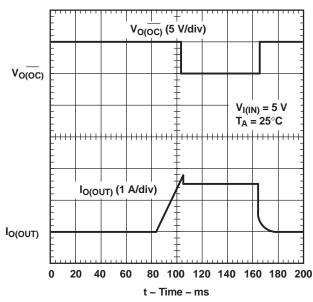


Figure 9. TPS2032, Ramped Load on Enabled Device



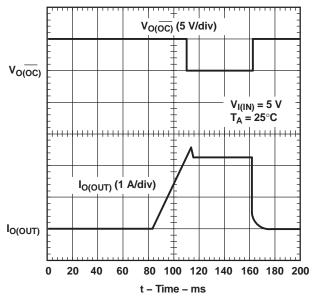


Figure 10. TPS2033, Ramped Load on Enabled Device

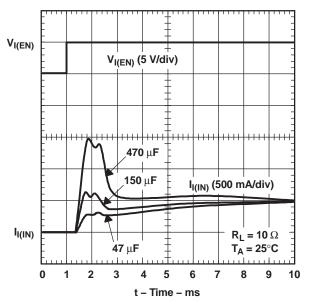


Figure 12. TPS2034, Inrush Current

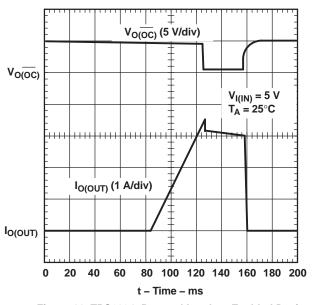


Figure 11. TPS2034, Ramped Load on Enabled Device

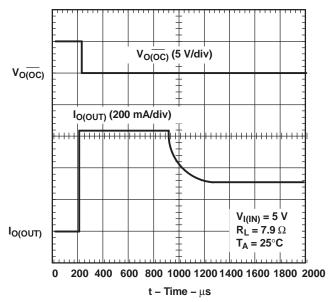


Figure 13. 7.9-Ω Load Connected to an Enabled TPS2030 Device



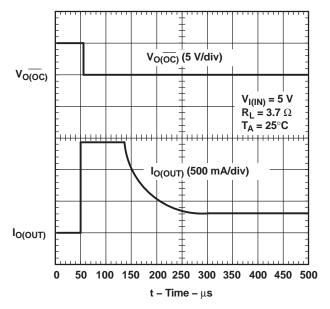


Figure 14. 3.7-Ω Load Connected to an Enabled TPS2030 Device

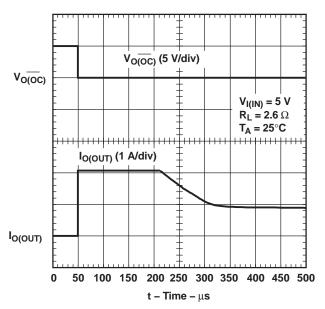


Figure 16. 2.6-Ω Load Connected to an Enabled TPS2031 Device

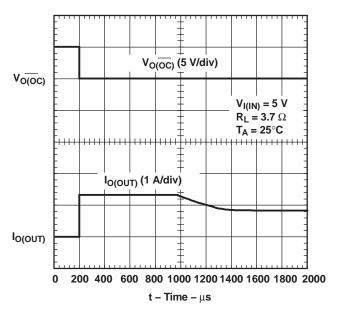


Figure 15. 3.7-Ω Load Connected to an Enabled TPS2031 Device

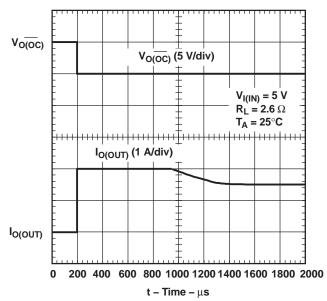


Figure 17. 2.6-Ω Load Connected to an Enabled TPS2032 Device



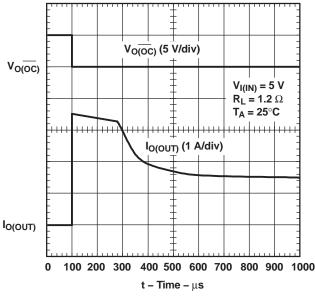


Figure 18. 1.2-Ω Load Connected to an Enabled TPS2032 Device

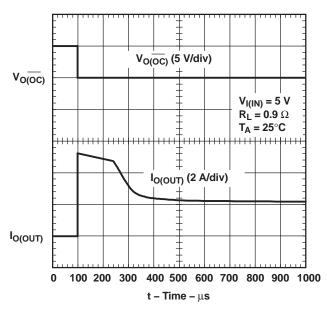


Figure 20. 0.9-Ω Load Connected to an Enabled TPS2033 Device

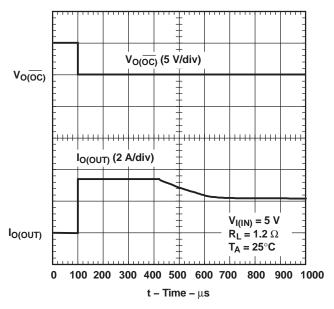


Figure 19. 1.2-Ω Load Connected to an Enabled TPS2033 Device

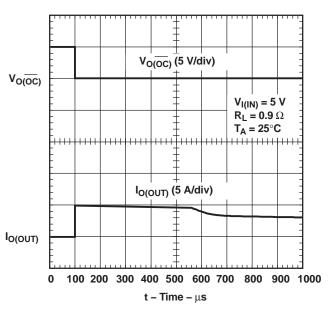


Figure 21. 0.9-Ω Load Connected to an Enabled TPS2034 Device



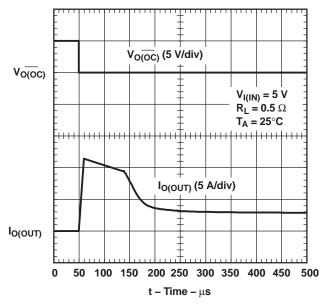


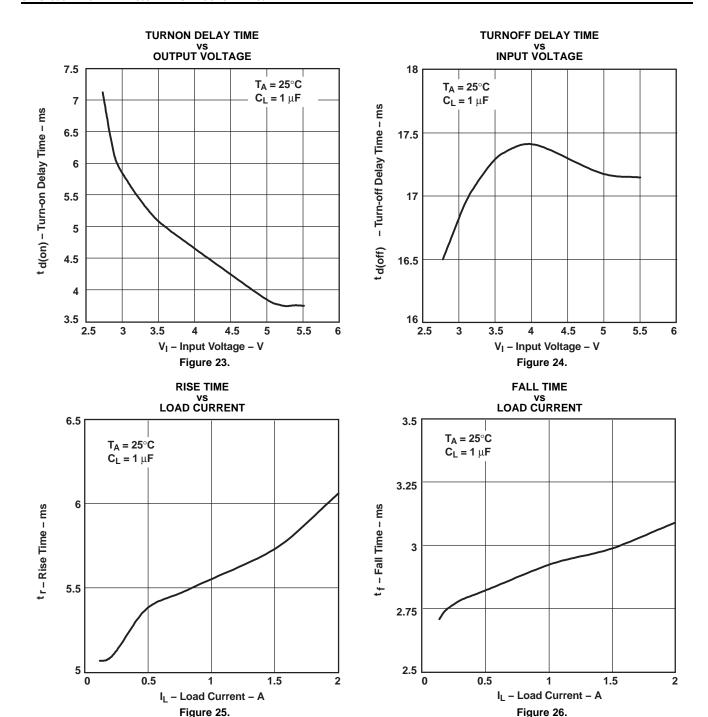
Figure 22. 0.5- Ω Load Connected to an Enabled TPS2034 Device

TYPICAL CHARACTERISTICS

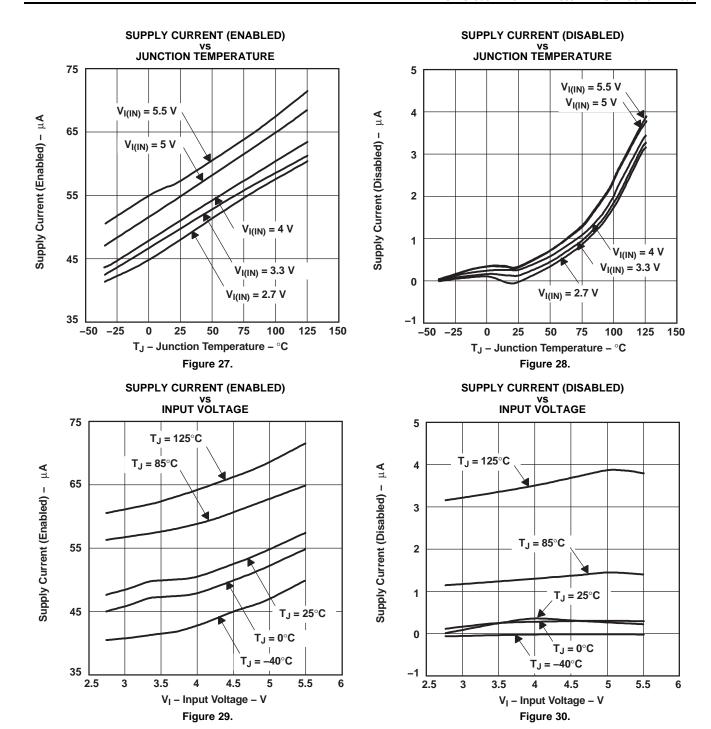
TABLE OF GRAPHS

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	Supply current (enabled)	vs Input voltage	29
	Supply current (disabled)	vs Input voltage	30
	Chart sine it summed limit	vs Input voltage	31
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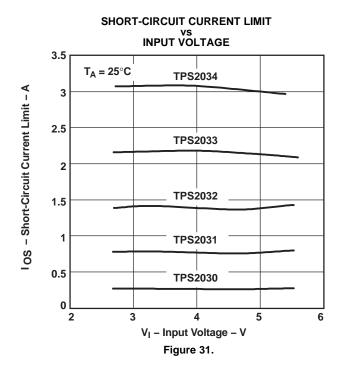




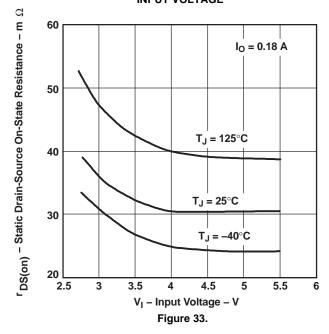




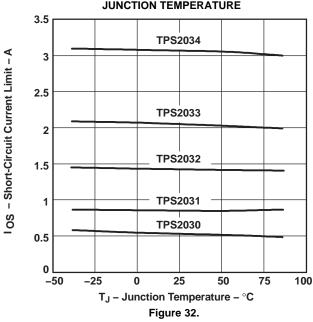




STATIC DRAIN-SOURCE ON-STATE RESISTANCE vs INPUT VOLTAGE



SHORT-CIRCUIT CURRENT LIMIT VS JUNCTION TEMPERATURE



STATIC DRAIN-SOURCE ON-STATE RESISTANCE vs JUNCTION TEMPERATURE

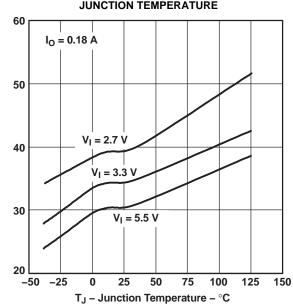
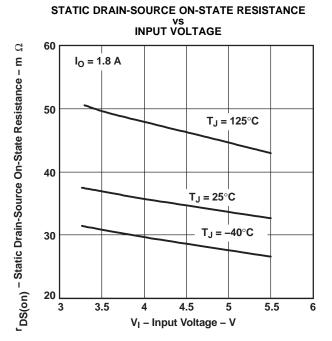


Figure 34.

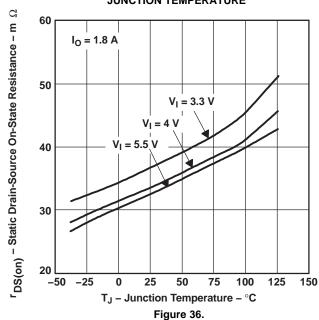
 $C_{\mathbf{i}}$

^rDS(on) - Static Drain-Source On-State Resistance - m

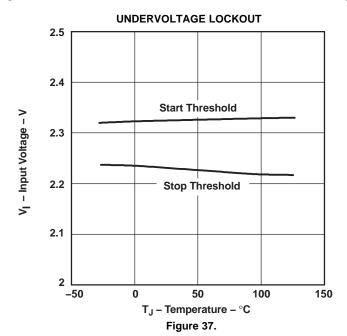




STATIC DRAIN-SOURCE ON-STATE RESISTANCE vs JUNCTION TEMPERATURE







APPLICATION INFORMATION

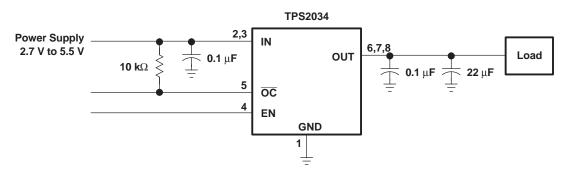


Figure 38. Typical Application

POWER SUPPLY CONSIDERATIONS

A 0.01- μF to 0.1- μF ceramic bypass capacitor between IN and GND, close to the device, is recommended. Placing a high-value electrolytic capacitor on the output and input pins is recommended when the output load is heavy. This precaution reduces power supply transients that may cause ringing on the input. Additionally, bypassing the output with a 0.01- μF to 0.1- μF ceramic capacitor improves the immunity of the device to short-circuit transients.

OVERCURRENT

A sense FET checks for overcurrent conditions. Unlike current-sense resistors, sense FETs do not increase the series resistance of the current path. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Complete shutdown occurs only if the fault is present long enough to activate thermal limiting.

Three possible overload conditions can occur. In the first condition, the output has been shorted before the device is enabled or before $V_{I(IN)}$ has been applied (see Figure 6). The TPS203x senses the short and immediately switches into a constant-current output.

In the second condition, the excessive load occurs while the device is enabled. At the instant the excessive load occurs, very high currents may flow for a short time before the current-limit circuit can react (see Figure 13 through Figure 22). After the current-limit circuit has tripped (reached the overcurrent trip threshold) the device switches into constant-current mode.

In the third condition, the load has been gradually increased beyond the recommended operating current. The current is permitted to rise until the current-limit threshold is reached or until the thermal limit of the device is exceeded (see Figure 7 through Figure 11). The TPS203x is capable of delivering current up to the current-limit threshold without damaging the device. Once the threshold has been reached, the device switches into its constant-current mode.

OC RESPONSE

The \overline{OC} open-drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output will remain asserted until the overcurrent or overtemperature condition is removed. Connecting a heavy capacitive load to an enabled device can cause momentary false overcurrent reporting from the inrush current flowing through the device, charging the downstream capacitor. An RC filter can be connected to the \overline{OC} pin to reduce false overcurrent reporting. Using low-ESR electrolytic capacitors on the output lowers the inrush current flow through the device during hot-plug events by providing a low impedance energy source, thereby reducing erroneous overcurrent reporting.



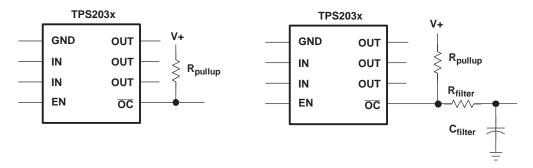


Figure 39. Typical Circuit for OC Pin and RC Filter for Damping Inrush OC Responses

POWER DISSIPATION AND JUNCTION TEMPERATURE

The low on-resistance on the n-channel MOSFET allows small surface-mount packages, such as SOIC, to pass large currents. The thermal resistances of these packages are high compared to those of power packages; it is good design practice to check power dissipation and junction temperature. The first step is to find $r_{DS(on)}$ at the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read $r_{DS(on)}$ from Figure 33 through Figure 36. Next, calculate the power dissipation using:

$$P_D = r_{DS(on)} \times l^2 \tag{1}$$

Finally, calculate the junction temperature:

$$T_J = P_D \times R_{\theta JA} + T_A \tag{2}$$

Where:

T_A = Ambient Temperature °C

 $R_{A,IA}$ = Thermal resistance SOIC = 172°C/W, PDIP = 106°C/W

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation, using the calculated value as the new estimate. Two or three iterations are generally sufficient to get an acceptable answer.

THERMAL PROTECTION

Thermal protection prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The faults force the TPS203x into constant current mode, which causes the voltage across the high-side switch to increase; under short-circuit conditions, the voltage across the switch is equal to the input voltage. The increased dissipation causes the junction temperature to rise to high levels. The protection circuit senses the junction temperature of the switch and shuts it off. Hysteresis is built into the thermal sense circuit, and after the device has cooled approximately 20 degrees, the switch turns back on. The switch continues to cycle in this manner until the load fault or input power is removed.

UNDERVOLTAGE LOCKOUT (UVLO)

An undervoltage lockout ensures that the power switch is in the off state at powerup. Whenever the input voltage falls below approximately 2 V, the power switch is quickly turned off. This facilitates the design of hot-insertion systems where it is not possible to turn off the power switch before input power is removed. The UVLO also keeps the switch from being turned on until the power supply has reached at least 2 V, even if the switch is enabled. Upon reinsertion, the power switch will be turned on, with a controlled rise time to reduce EMI and voltage overshoots.



GENERIC HOT-PLUG APPLICATIONS (Figure 40)

In many applications it may be necessary to remove modules or pc boards while the main unit is still operating. These are considered hot-plug applications. Such implementations require the control of current surges seen by the main power supply and the card being inserted. The most effective way to control these surges is to limit and slowly ramp the current and voltage being applied to the card, similar to the way in which a power supply normally turns on. Because of the controlled rise times and fall times of the TPS203x series, these devices can be used to provide a softer start-up to devices being hot-plugged into a powered system. The UVLO feature of the TPS203x also ensures the switch will be off after the card has been removed, and the switch will be off during the next insertion. The UVLO feature ensures a soft start with a controlled rise time for every insertion of the card or module.

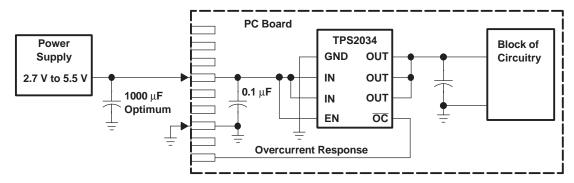


Figure 40. Typical Hot-Plug Implementation

By placing the TPS203x between the V_{CC} input and the rest of the circuitry, the input power will reach this device first after insertion. The typical rise time of the switch is approximately 9 ms, providing a slow voltage ramp at the output of the device. This implementation controls system surge currents and provides a hot-plugging mechanism for any device.





29-Oct-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TPS2030D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2030	Samples
TPS2030DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2030	Samples
TPS2030DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2030	Samples
TPS2030DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2030	Samples
TPS2030P	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	TPS2030P	Samples
TPS2031D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2031	Samples
TPS2031DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2031	Samples
TPS2031DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2031	Samples
TPS2031DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2031	Samples
TPS2031P	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	TPS2031P	Samples
TPS2032D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2032	Samples
TPS2032DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2032	Samples
TPS2032DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2032	Samples
TPS2032DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2032	Samples
TPS2033D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2033	Samples
TPS2033DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2033	Samples
TPS2033DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2033	Samples



PACKAGE OPTION ADDENDUM

29-Oct-2017

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TPS2033DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2033	Samples
TPS2034D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2034	Samples
TPS2034DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2034	Samples
TPS2034DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2034	Samples
TPS2034DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	2034	Samples
TPS2034P	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	TPS2034P	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

29-Oct-2017

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OTHER QUALIFIED VERSIONS OF TPS2030, TPS2032:

Automotive: TPS2030-Q1, TPS2032-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



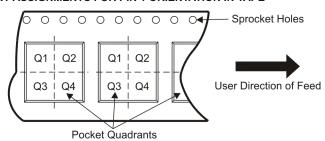
TAPE AND REEL INFORMATION



TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS2030DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TPS2031DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TPS2032DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TPS2033DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TPS2034DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1





*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS2030DR	SOIC	D	8	2500	340.5	338.1	20.6
TPS2031DR	SOIC	D	8	2500	340.5	338.1	20.6
TPS2032DR	SOIC	D	8	2500	340.5	338.1	20.6
TPS2033DR	SOIC	D	8	2500	340.5	338.1	20.6
TPS2034DR	SOIC	D	8	2500	340.5	338.1	20.6

D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.



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